

<b>Notice of References Cited</b>	Application/Control No. 10/695,197	Applicant(s)/Patent Under Reexamination FUJIYAMA ET AL.	
	Examiner Nguyen T. Ha	Art Unit 2831	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,723,927	04-2004	Fan et al.	174/262
	B	US-6,593,535	07-2003	Gailus, Mark W.	174/262
	C	US-6,384,341	05-2002	Rothermel et al.	174/255
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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